

ULN2003A, ULQ2003A

High Voltage, High Current Darlington Transistor Arrays

The seven NPN Darlington connected transistors in these arrays are well suited for driving lamps, relays, or printer hammers in a variety of industrial and consumer applications. Their high breakdown voltage and internal suppression diodes insure freedom from problems associated with inductive loads. Peak inrush currents to 500 mA permit them to drive incandescent lamps.

The ULx2003A with a 2.7 k Ω series input resistor is well suited for systems utilizing a 5.0 V TTL or CMOS Logic.

Features

- These are Pb-Free Devices

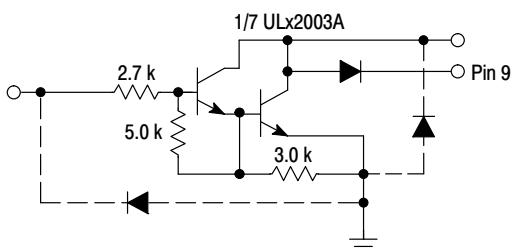


Figure 1. Representative Schematic Diagram

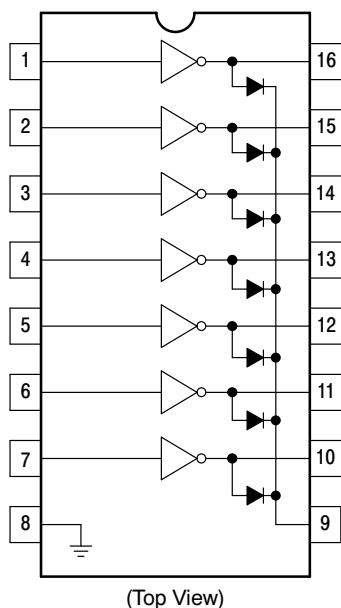


Figure 2. Pin Connections

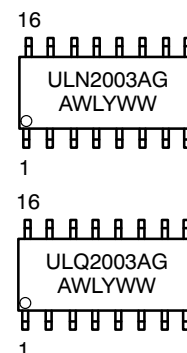


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MARKING DIAGRAMS



A = Assembly Location
WL = Wafer Lot
Y = Year
WW = Work Week
G = Pb-Free Package

ORDERING INFORMATION

Device	Package	Shipping†
ULN2003ADR2G	SOIC-16 (Pb-Free)	2500 Tape & Reel
ULQ2003ADR2G	SOIC-16 (Pb-Free)	2500 Tape & Reel

†For information on tape and reel specifications, including part orientation and tape sizes, please refer to our Tape and Reel Packaging Specifications Brochure, BRD8011/D.

ULN2003A, ULQ2003A

MAXIMUM RATINGS ($T_A = 25^\circ\text{C}$, and rating apply to any one device in the package, unless otherwise noted.)

Rating	Symbol	Value	Unit
Output Voltage	V_O	50	V
Input Voltage	V_I	30	V
Collector Current – Continuous	I_C	500	mA
Base Current – Continuous	I_B	25	mA
Operating Ambient Temperature Range ULN2003A ULQ2003A	T_A	-20 to +85 -40 to +85	$^\circ\text{C}$
Storage Temperature Range	T_{stg}	-55 to +150	$^\circ\text{C}$
Junction Temperature	T_J	150	$^\circ\text{C}$
Thermal Resistance, Junction-to-Ambient Case 751B, D Suffix	$R_{\theta JA}$	100	$^\circ\text{C/W}$
Thermal Resistance, Junction-to-Case Case 751B, D Suffix	$R_{\theta JC}$	20	$^\circ\text{C/W}$
Electrostatic Discharge Sensitivity (ESD) Human Body Model (HBM) Machine Model (MM) Charged Device Model (CDM)	ESD	2000 400 1500	V

Stresses exceeding Maximum Ratings may damage the device. Maximum Ratings are stress ratings only. Functional operation above the Recommended Operating Conditions is not implied. Extended exposure to stresses above the Recommended Operating Conditions may affect device reliability.

ULN2003A, ULQ2003A

ELECTRICAL CHARACTERISTICS (T_A = 25°C, unless otherwise noted)

Characteristic	Symbol	Min	Typ	Max	Unit
Output Leakage Current (V _O = 50 V, T _A = +85°C) (V _O = 50 V, T _A = +25°C)	I _{CEX}	– –	– –	100 50	μA
Collector-Emitter Saturation Voltage (I _C = 350 mA, I _B = 500 μA) (I _C = 200 mA, I _B = 350 μA) (I _C = 100 mA, I _B = 250 μA)	V _{CE(sat)}	– – –	1.1 0.95 0.85	1.6 1.3 1.1	V
Input Current – On Condition (V _I = 3.85 V)	I _{I(on)}	–	0.93	1.35	mA
Input Voltage – On Condition (V _{CE} = 2.0 V, I _C = 200 mA) (V _{CE} = 2.0 V, I _C = 250 mA) (V _{CE} = 2.0 V, I _C = 300 mA)	V _{I(on)}	– – –	– – –	2.4 2.7 3.0	V
Input Current – Off Condition (I _C = 500 μA, T _A = 85°C)	I _{I(off)}	50	100	–	μA
DC Current Gain (V _{CE} = 2.0 V, I _C = 350 mA)	h _{FE}	1000	–	–	–
Input Capacitance	C _I	–	15	30	pF
Turn-On Delay Time (50% E _I to 50% E _O)	t _{on}	–	0.25	1.0	μs
Turn-Off Delay Time (50% E _I to 50% E _O)	t _{off}	–	0.25	1.0	μs
Clamp Diode Leakage Current (V _R = 50 V)	I _R	T _A = +25°C	–	50	μA
		T _A = +85°C	–	100	
Clamp Diode Forward Voltage (I _F = 350 mA)	V _F	–	1.5	2.0	V

ULN2003A, ULQ2003A

Typical Performance Curves - $T_A = 25^\circ\text{C}$

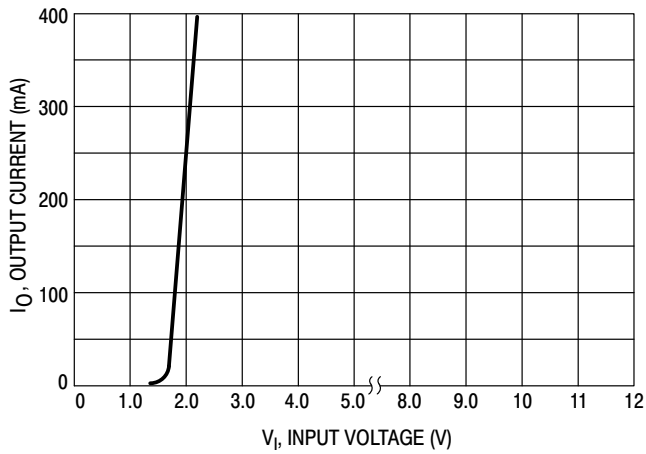


Figure 3. Output Current versus Input Voltage

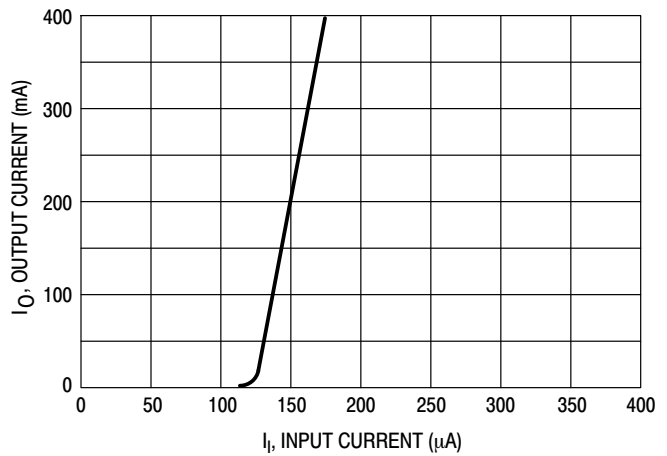


Figure 4. Output Current versus Input Current

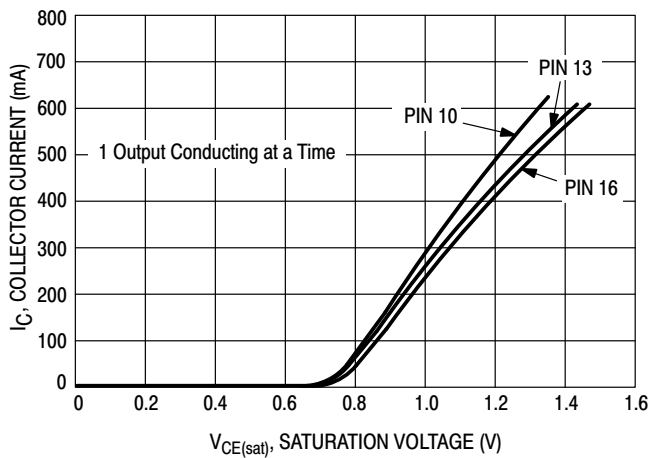


Figure 5. Typical Output Characteristics

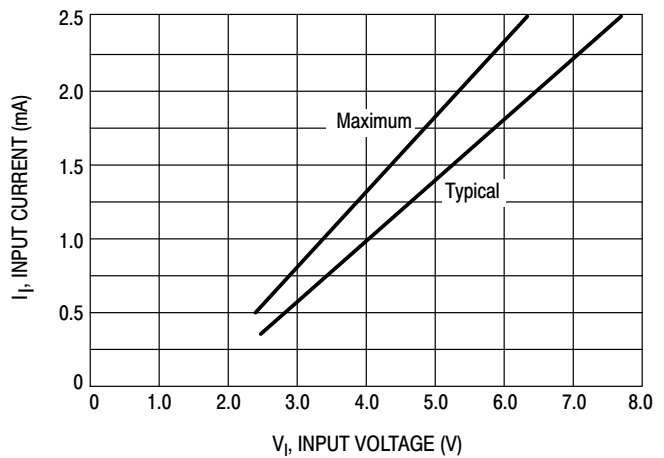


Figure 6. Input Characteristics

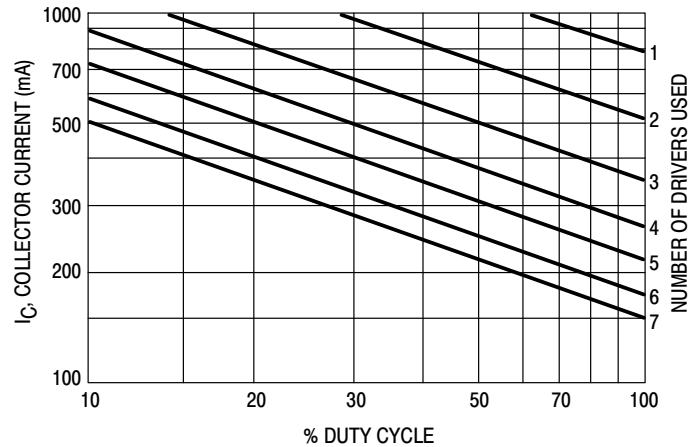


Figure 7. Maximum Collector Current versus Duty Cycle (and Number of Drivers in Use)

